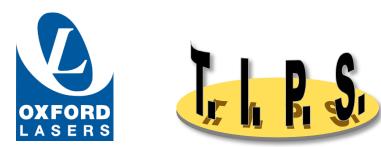


Solutions to New Challenges in Advanced Vertical Guide Plates

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Summary

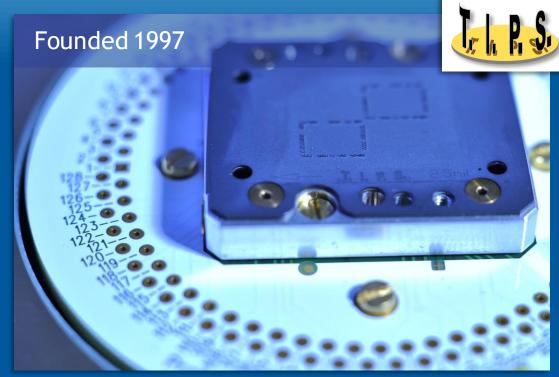
Introduction Motivation : A need in the market for higher current Probe Cards A Simple Mechanical Model Manufacturing Challenges Results of 1st Trial Results of 2nd Trial Discussion Follow-on Work Conclusion

Introduction



Specializing in the manufacture of guide plates:

- Over 20 years experience in guide plate production
- World Class subcontract micromachining facility
- Manufacturer of production laser tools



Specializing in the design and manufacture of test interfaces for semiconductor test:

- High Power Applications
- Probe Cards for Sensor Devices
- Automotive RADAR

Introduction

Trends in Vertical Probe Cards :

1) Smaller Holes

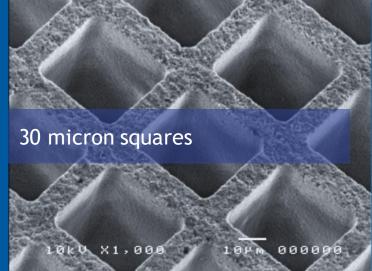
2) Tighter Pitch

The focus of this presentation is on tighter pitch :

- two years ago, we focused on achieving tighter pitch

- here, with T.I.P.S, we will show a practical example





Motivation

T.I.P.S have noted an increasing requirement for high current probe cards :

- Requests for 3000A and more
- Vertical probe cards allow much higher current densities compared to cantilever probe cards
- High pin count and high needle density required:
 - Reducing needle pitch to increase overall current
 - Mechanical stress in ceramic guide plates could be a limiting factor

Investigation of **minimum** feasible **hole pitch** in ceramic guide plates

Our Approach

Development of a basic mechanical model to obtain statements about the mechanical stresses in the ceramic guide plates

Conduct an experimental investigation - considering the findings from the mechanical model

- Discuss feasible wall thickness
- Experimental setup with specified hole patterns
- > Manufacturing of the ceramic guide plates
- > Durability testing of the assembled vertical probe head

(Oxford Lasers and T.I.P.S.) (Provided by T.I.P.S.) (Oxford Lasers) (Conducted at T.I.P.S.)

Revisit the mechanical model with outcome from experimental investigations Goal:

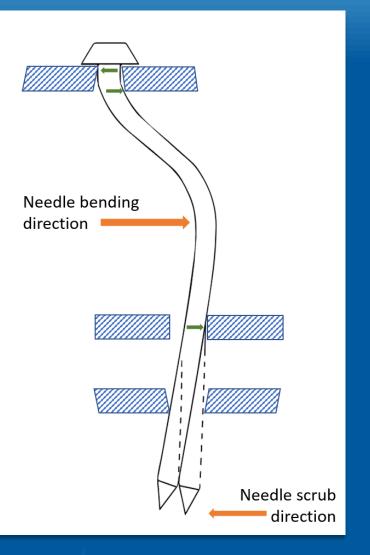
Establish guidelines for designing needle arrangements for given current and pad size / shapes

A Simple Mechanical Model

Mechanical model – Needle forces

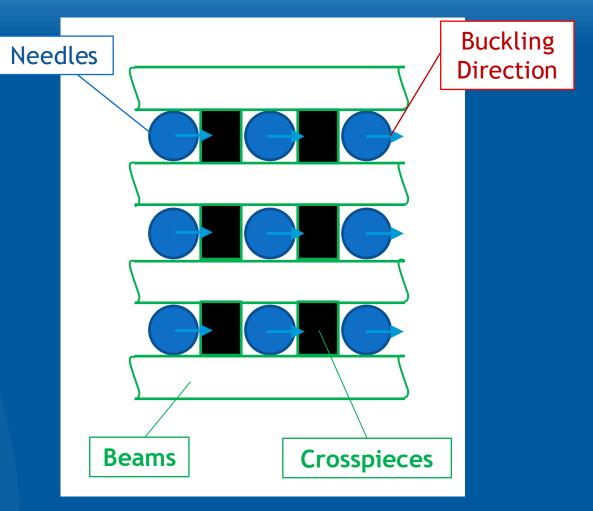
Bending forces can be calculated from bending line of needle, dependent on:

- Needle diameter and length
- Distance between ceramic plates
- Overtravel
- Young's modulus of needle material



A Simple Model

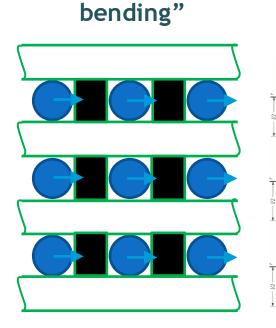
- Simple hole pattern in ceramic plate
- Material between holes to be considered cuboidal
- Buckling direction parallel to beam alignment



A Simple Model

Crosspiece

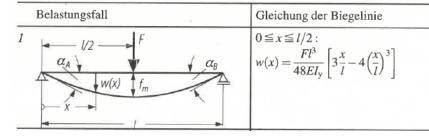
Beam



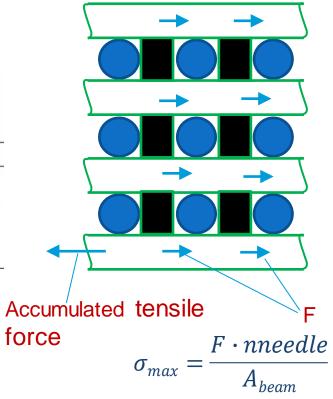
Calculated as "beam in

C 22 Festigkeitslehre – 2 Beanspruchung stabförmiger Bauteile

Tabelle 5 a. Biegelinien von statisch bestimmten Trägern mit konstantem Querschnitt



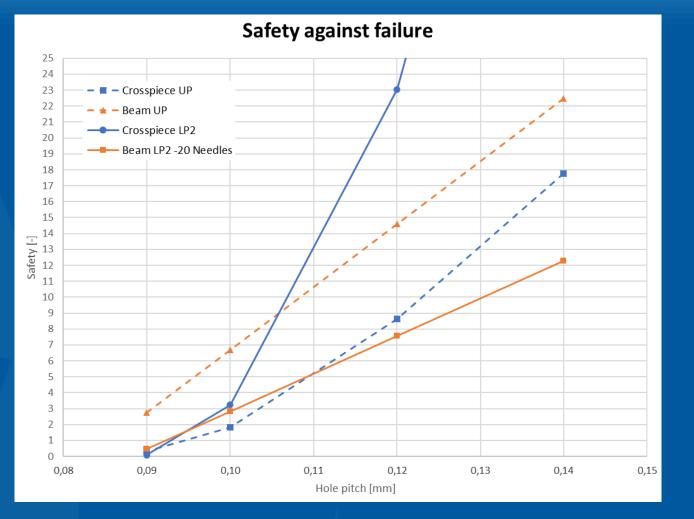
Stressed by tensile force of crosspiece



Simple Mechanical Model - Findings

- Simplified model provides basic correlation, but has too many uncertainties
- Absolute values are not that reliable, but
 - Upper plate:
 - Crosspiece seems more critical
 - Lower plate:
 - Depending on number of needles in buckling direction, beam seems more critical

Experimental investigations needed

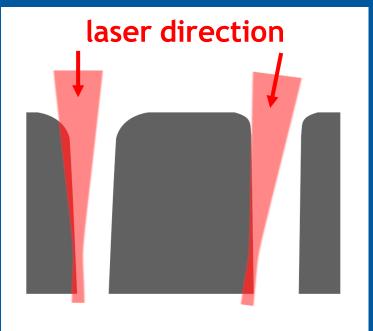


Manufacturing Challenges

Drilling holes on tighter and tighter pitch

Some factors to be considered :

- Variety of hole diameters in different plates making up each probe head
- > Deliberate taper requirements to assist needle movement
- Entry rounding on the laser entry side of the drilled hole
- Structural integrity of wall

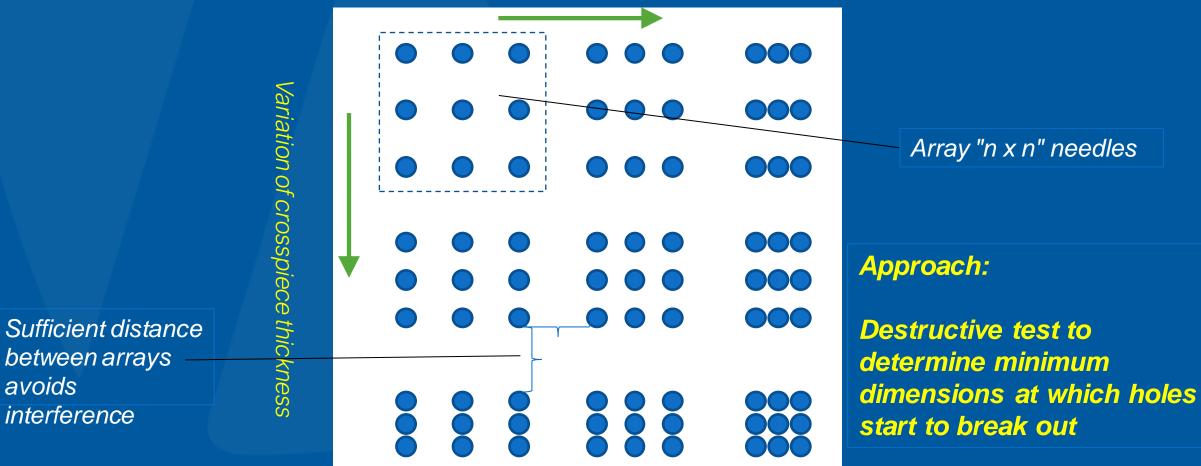


Experimental Work – First Trial

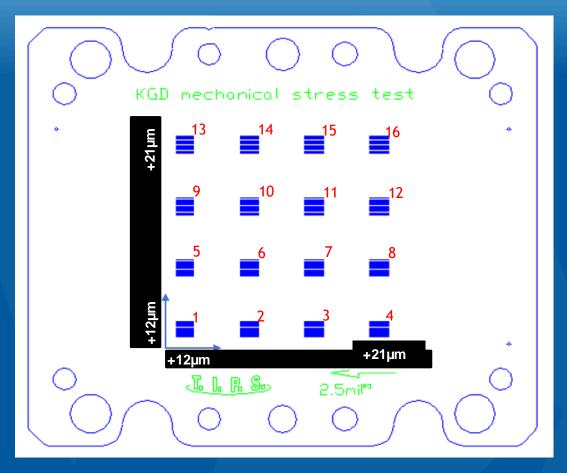
avoids

Variation of hole pitch in both directions to find out critical wall thickness

Variation of beam thickness



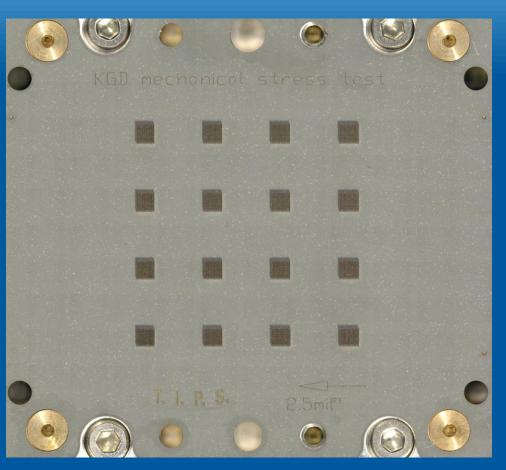
First Trial





Overtravel : Maximum Overtravel Touchdowns : > 20,000

Alan Ferguson Sebastian Salbrechter



Test Method :

Disassemble probe head Check for ceramic plate failure Repeat

Results from First Trial

Pleasingly all arrays passed :
no broken ceramics
nothing exciting to show

Shows that model is just an indicator

Next step - To reduce the hole pitch further

Test plates with hole to hole wall thickness of 10 microns and 8 microns

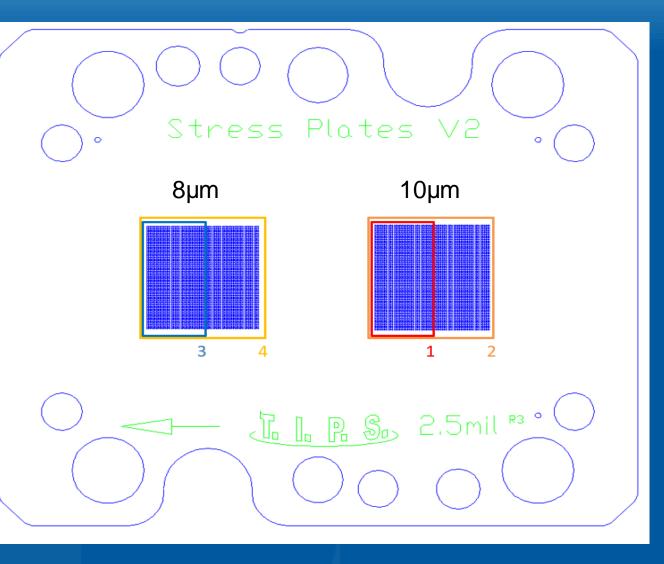
Second Trial

Two further test conditions :

- Minimum wall thickness 10 microns
 - Array 1
 - Array 2
- Minimum wall thickness 8 microns
 - Array 3
 - Array 4

Testing Protocol :

Maximum overtravel 50,000 touchdowns Disassemble probe head Check for ceramic plate failure Repeat



Second Trial Results

Results from the two further test conditions :

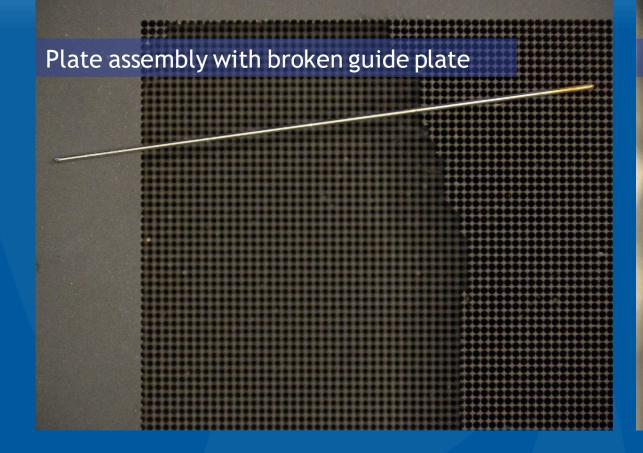
- Minimum wall thickness 10 microns
 Array 1
 - Array 2

Minimum wall thickness 8 microns
 Array 3 ×

Testing Protocol :

Maximum overtravel 50,000 touchdowns Disassemble probe head Check for ceramic plate failure Repeat

Results from Second Trial



Broken guide plate clearly visible



Discussion

• Simple mechanical model gives good understanding of forces involved

- Not accurate enough to do predictions
- Calculations err "on the side of safety"
- Experimental verification gave good insights into actual mechanical stress limits
- Raises questions on the limits of tight pitch in certain circumstances
- Expect to be different for different plate thicknesses and materials

Follow-on Work

Improve the Mechanical Model

Check repeatability of this work under a variety of conditions

Investigate other materials

Conclusion

- Simple model gives some indication, but needs further refinement / experimental investigation much more complex but good to get understanding of forces
- Demonstrated an improvement on pitch reduction performance of 26% in both directions
 - \succ Increase of current density of almost 60% on same chip size!
 - Possible to design a Probe Card that is both :
 - manufacturable and
 - has a safety margin built in
 - Satisfies the customers high current requirements

Thanks

My thanks for this work go to :

From T.I.P.S :

Dr Rainer Gaggl Sebastian Salbrechter Meinhart Jeschke

From Oxford Lasers :

Michael Gaukgroger Mark Cheverton

Thank you for your Attention